

April 1988 Revised August 1999

74F378

Parallel D-Type Register with Enable

General Description

The 74F378 is a 6-bit register with a buffered common Enable. This device is similar to the 74F174, but with common Enable rather than common Master Reset.

Features

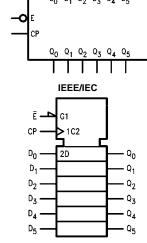
- 6-bit high-speed parallel register
- Positive edge-triggered D-type inputs
- Fully buffered common clock and enable inputs
- Input clamp diodes limit high-speed termination effects
- Full TTL and CMOS compatible

Ordering Code:

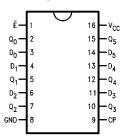
Order Number	Package Number	Package Description
74F378SC	M16A	16-Lead Small Outline Integrated Circuit (SOIC), JEDEC MS-012, 0.150 Narrow
74F378SJ	M16D	16-Lead Small Outline Package (SOP), EIAJ TYPE II, 5.3mm Wide
74F378PC	N16E	16-Lead Plastic Dual-In-Line Package (PDIP), JEDEC MS-001, 0.300 Wide

Devices also available in Tape and Reel. Specify by appending the suffix letter "X" to the ordering code.

Logic Symbols



Connection Diagram



Unit Loading/Fan Out

Dia Nama	B tatio	U.L.	Input I _{IH} /I _{IL}		
Pin Names	Description	HIGH/LOW	Output I _{OH} /I _{OL}		
Ē	Enable Input (Active LOW)	1.0/1.0	20 μA/–0.6 mA		
D ₀ –D ₅	Data Inputs	1.0/1.0	20 μA/-0.6 mA		
CP	Clock Pulse Input (Active Rising Edge)	1.0/1.0	20 μA/–0.6 mA		
Q ₀ -Q ₅	Outputs	50/33.3	−1 mA/20 mA		

Functional Description

The 74F378 consists of six edge-triggered D-type flip-flops with individual D inputs and Q inputs. The Clock (CP) and Enable (\overline{E}) inputs are common to all flip-flops.

When the $\overline{\mathsf{E}}$ input is LOW, new data is entered into the register on the LOW-to-HIGH transition of the CP input. When the $\overline{\mathsf{E}}$ input is HIGH the register will retain the present data independent of the CP input.

Truth Table

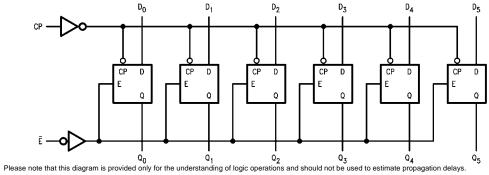
	Output		
Ē	СР	D _n	Q _n
Н	~	Х	No Change
L	~	Н	Н
L	~	L	L

H = HIGH Voltage Level L = LOW Voltage Level

X = Immaterial

∠ = LOW-to-HIGH Clock Transition

Logic Diagram



Absolute Maximum Ratings(Note 1)

-65°C to +150°C Storage Temperature Ambient Temperature under Bias -55°C to +125°C

Junction Temperature under Bias -55°C to +150°C V_{CC} Pin Potential to Ground Pin -0.5V to +7.0V

Input Voltage (Note 2) -0.5V to +7.0VInput Current (Note 2) -30 mA to +5.0 mA

Voltage Applied to Output

in HIGH State (with $V_{CC} = 0V$)

Standard Output -0.5V to V_{CC}

3-STATE Output -0.5V to +5.5V

Current Applied to Output

in LOW State (Max) twice the rated I_{OL} (mA)

Recommended Operating Conditions

Free Air Ambient Temperature 0°C to +70°C Supply Voltage +4.5V to +5.5V

Note 1: Absolute maximum ratings are values beyond which the device may be damaged or have its useful life impaired. Functional operation under these conditions is not implied.

Note 2: Either voltage limit or current limit is sufficient to protect inputs.

DC Electrical Characteristics

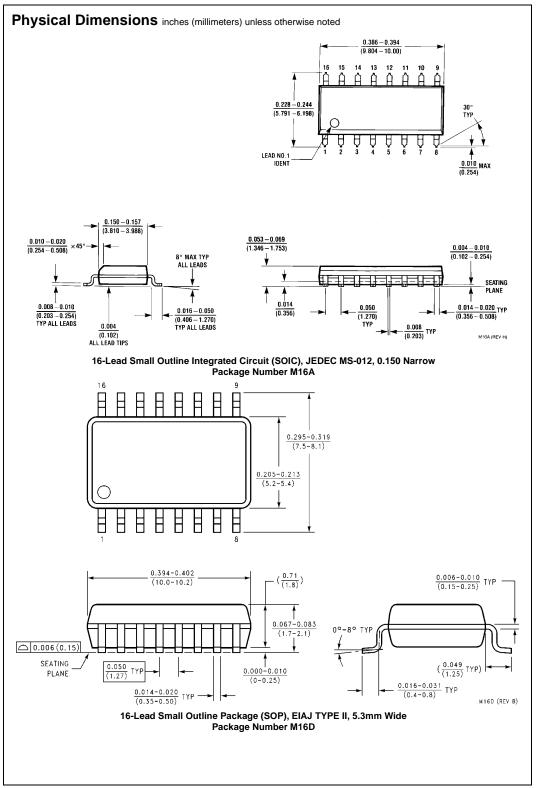
Symbol	Parameter		Min	Тур	Max	Units	v _{cc}	Conditions
V _{IH}	Input HIGH Voltage		2.0			V		Recognized as a HIGH Signal
V _{IL}	Input LOW Voltage				0.8	V		Recognized as a LOW Signal
V _{CD}	Input Clamp Diode Voltage				-1.2	V	Min	I _{IN} = -18 mA
V _{OH}	Output HIGH	10% V _{CC}	2.5			V	Min	I _{OH} = -1 mA
	Voltage	$5\% V_{CC}$	2.7			V	IVIIN	$I_{OH} = -1 \text{ mA}$
V _{OL}	Output LOW	10% V _{CC}			0.5	V	Min	1 20 m A
	Voltage				0.5	V	IVIII	I _{OL} = 20 mA
I _{IH}	Input HIGH				5.0			1/ 0.71/
	Current				5.0	μΑ	Max	$V_{IN} = 2.7V$
I _{BVI}	Input HIGH Current				7.0		Max	1/ 7.01/
	Breakdown Test				7.0	μА	IVIAX	V _{IN} = 7.0V
I _{CEX}	Output HIGH				50	^	Max	V -V
	Leakage Current				50	μА	IVIAX	$V_{OUT} = V_{CC}$
V _{ID}	Input Leakage		4.75			V	0.0	$I_{ID} = 1.9 \mu A$
	Test		4.75			V	0.0	All Other Pins Grounded
I _{OD}	Output Leakage				3.75		0.0	V _{IOD} = 150 mV
	Circuit Current				3.75	μА	0.0	All Other Pins Grounded
I _{IL}	Input LOW Current				-0.6	mA	Max	$V_{IN} = 0.5V$
Ios	Output Short-Circuit Current		-60		-150	mA	Max	V _{OUT} = 0V
I _{CCL}	Power Supply Current			30	45	mA	Max	V _O = LOW

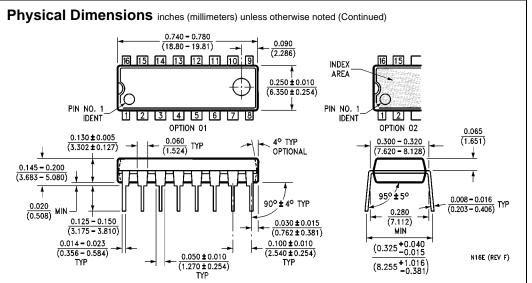
AC Electrical Characteristics

Symbol	Parameter	$T_{A} = +25^{\circ}C$ $V_{CC} = +5.0V$ $C_{L} = 50 \text{ pF}$			$T_A = -55 ^{\circ} C \text{ to } +125 ^{\circ} C$ $V_{CC} = +5.0 V$ $C_L = 50 \text{ pF}$		$T_A = 0$ °C to +70°C $V_{CC} = +5.0V$ $C_L = 50 \text{ pF}$		Units
		Min	Тур	Max	Min	Max	Min	Max	
f _{MAX}	Maximum Input Frequency	80	100		70		80		MHz
t _{PLH}	Propagation Delay	3.0	5.5	7.5	3.0	10.0	3.0	8.5	ns
t _{PHL}	CP to Q _n	3.5	6.0	8.5	3.5	10.5	3.5	9.5	115

AC Operating Requirements

		$T_A = +25$ °C $V_{CC} = +5.0V$		$T_A = -55$ °C to +125°C $V_{CC} = +5.0V$		$T_A = 0$ °C to +70°C $V_{CC} = +5.0V$		Units
Symbol	Parameter							
		Min	Max	Min	Max	Min	Max	
t _S (H)	Setup Time, HIGH or LOW	4.0		5.0		4.0		
t _S (L)	D _n to CP	4.0		5.0		4.0		20
t _H (H)	Hold Time, HIGH or LOW	0		2.0		0		ns
t _H (L)	D _n to CP	0		2.0		0		
t _S (H)	Setup Time, HIGH or LOW	6.0		4.5		6.0		
t _S (L)	E to CP	10.0		13.0		10.0		
t _H (H)	Hold Time, HIGH or LOW	0		0		0		ns
t _H (L)	E to CP	0		0		0		
t _W (H)	CP Pulse Width	4.0		5.0		4.0		20
t _W (L)	HIGH or LOW	6.0		7.5		6.0		ns





16-Lead Plastic Dual-In-Line Package (PDIP), JEDEC MS-001, 0.300 Wide Package Number N16E

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